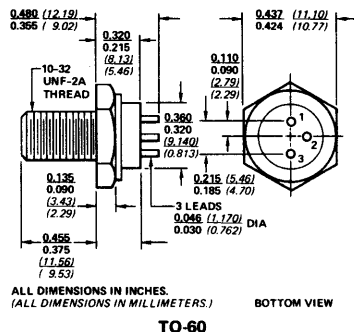


N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTOR



FOR POWER AMPLIFIERS AND SWITCHES

- High Power Capability — 10 W
- High g_{fs} — 80,000 μmhos Minimum
- High I_{DSS} — 300 mA Minimum
- No Thermal Runaway
- No Secondary Breakdown



PIN	OUT
1	S
2	D
3	G

ABSOLUTE MAXIMUM RATINGS (25°C)

Gate-Drain and Gate-Source Voltage	-25 V
Drain Current	900 mA
Total Device Dissipation at 25°C	
Case Temperature (Note 2)	10 W
Storage Temperature Range	-65 to +150°C
Operating Junction Temperature Range	-55 to +150°C

ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)

Characteristic		Min	Max	Unit	Test Conditions	
S T A T I C	I_{GSS} Gate Reverse Current		-1	nA	$V_{GS} = -15 \text{ V}, V_{DS} = 0$	
			-1	μA		150°C
	$I_{D(off)}$ Drain Cutoff Current		1	nA	$V_{DS} = 5 \text{ V}, V_{GS} = -10 \text{ V}$	
			1	μA		150°C
D Y N	BV_{GSS} Gate-Source Breakdown Voltage	-25		V	$I_G = -1 \mu\text{A}, V_{DS} = 0$	
	$V_{GS(off)}$ Gate-Source Cutoff Voltage	-3.5	-8	V	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$	
	I_{DSS} Saturation Drain Current (Note 1)	300	900	mA	$V_{DS} = 10 \text{ V}, V_{GS} = 0$	
	$r_{DS(on)}$ Static Drain-Source On Resistance		10	Ω	$V_{GS} = 0, I_D = 10 \text{ mA}$	
D Y N	g_{fs} Common-Source Forward Transconductance (Note 3)	80,000	200,000	μmho	$V_{DS} = 10 \text{ V}, V_{GS} = 0$	$f = 1 \text{ kHz}$
	C_{iss} Common-Source Input Capacitance		35	pF	$V_{DS} = 0, V_{GS} = -10 \text{ V}$	$f = 1 \text{ MHz}$
	C_{rss} Common-Source Reverse Transfer Capacitance		15	pF	$V_{DS} = 0, V_{GS} = -10 \text{ V}$	$f = 1 \text{ MHz}$

NOTES:

1. Pulse test duration = 2 ms.
2. Derate linearly to 150°C case temperature at rate of 80 mW/°C.

NI

Performance Curves NZF

See Page 4-49

U257

MATCHED DUAL N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTOR

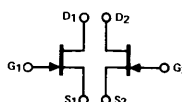
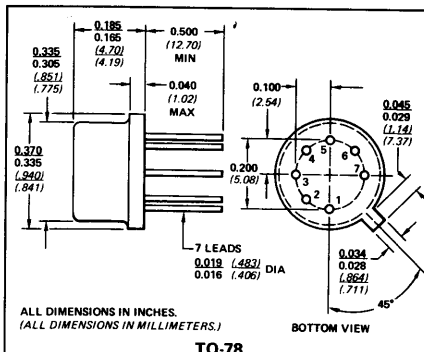


MATCHED FET PAIRS FOR WIDEBAND DIFFERENTIAL AMPLIFIERS

- g_{fs} greater than 5000 μmho from dc to 100 MHz
- Matched V_{GS} , g_{fs} and g_{os}

ABSOLUTE MAXIMUM RATINGS (25°C)

Gate-Drain or Gate-Source Voltage	-25 V
Gate Current	50 mA
Device Dissipation (Each Side), $T_A = 85^\circ\text{C}$ (Derate 3.85 mW/°C)	250 mW
Total Device Dissipation, $T_A = 85^\circ\text{C}$ (Derate 7.7 mW/°C)	500 mW
Storage Temperature Range	-65 to +150°C



PIN	OUT	PIN	OUT
1	S ₁	4	C
2	D ₁	5	S ₂
3	G ₁	6	D ₂
		7	G ₂

2

ELECTRICAL CHARACTERISTICS (25° unless otherwise noted)

Characteristic			Min	Max	Unit	Test Conditions	
1	S T A T I C	I_{GSS} Gate Reverse Current		-100	pA	$V_{GS} = 15 \text{ V}$, $V_{DS} = 0$	150°C
2			-250	nA			
3		BV_{GSS} Gate-Source Breakdown Voltage	-25		V	$I_G = -1 \mu\text{A}$, $V_{DS} = 0$	
4		$V_{GS(off)}$ Gate-Source Cutoff Voltage	-1	-5		$V_{DS} = 10 \text{ V}$, $I_D = 1 \text{ nA}$	
5		I_{DSS} Saturation Drain Current (Note 1)	5	40		mA	
6	D Y N A M I C	g_{fs} Common-Source Forward Transconductance	5000	10,000	μmho	$V_{DS} = 10 \text{ V}$, $I_D = 5 \text{ mA}$	$f = 1 \text{ kHz}$
7		g_{fs} Common-Source Forward Transconductance	5000	10,000		$V_{DG} = 10 \text{ V}$, $I_D = 5 \text{ mA}$	$f = 100 \text{ MHz}$
8		g_{os} Common-Source Output Conductance		150		$V_{DS} = 10 \text{ V}$, $I_D = 5 \text{ mA}$	$f = 1 \text{ kHz}$
9		g_{oss} Common-Source Output Conductance		150			$f = 100 \text{ MHz}$
10		C_{iss} Common-Source Input Capacitance		5	pF	$V_{DG} = 10 \text{ V}$, $I_D = 5 \text{ mA}$	$f = 1 \text{ MHz}$
11		C_{rss} Common-Source Reverse Transfer Capacitance		1.2			$f = 10 \text{ kHz}$
12		$\bar{e}_n$ Equivalent Input Noise Voltage		30			$\frac{\text{nV}}{\sqrt{\text{Hz}}}$
13	M A T C H I N G	$\frac{I_{DSS1}}{I_{DSS2}}$ Drain Current Ratio at Zero Gate Voltage (Note 1)	0.85	1		$V_{DS} = 10 \text{ V}$, $V_{GS} = 0$	
14		$ V_{GS1} - V_{GS2} $ Differential Gate-Source Voltage		100	mV	$V_{DG} = 10 \text{ V}$, $I_D = 5 \text{ mA}$	$f = 1 \text{ kHz}$
15		$\frac{g_{fs1}}{g_{fs2}}$ Transconductance Ratio	0.85	1			
16		$ g_{os1} - g_{os2} $ Differential Output Conductance		20	μmho		

NOTE:

1. Pulse test required, pulse width = 300 μs , duty cycle $\leq 30\%$.

NZF

Performance Curves NVA

See Page 4-48

N-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

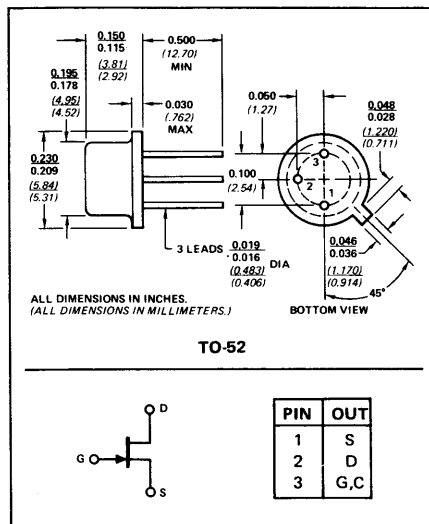


FOR ANALOG SWITCHES, COMMUTATORS,
AND CHOPPERS

- Low ON Resistance < 2.5 Ohms on U290
- $I_{D(off)} < 1$ nA

ABSOLUTE MAXIMUM RATINGS (25°C)

Reverse Gate-Drain or Gate-Source Voltage -30 V
 Gate Current 100 mA
 Drain Current 1.5 A
 Total Device Dissipation at 25°C
 Free-Air Temperature (Note 2) 300 mW
 Storage Temperature Range -65 to +150°C
 Lead Temperature
 (1/16" from case for 10 seconds) 300°C

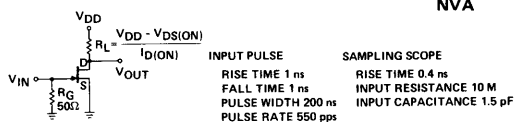


ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)

Characteristic		U290		U291		Unit	Test Conditions	
		Min	Max	Min	Max			
1	IGSS Gate Reverse Current		-1		-1	nA	VGS = -15 V, VDS = 0	150°C
2			-1		-1	μA		
3	BVGSS Gate-Source Breakdown Voltage	-30		-30		V	IG = -1 μA, VDS = 0	150°C
4	VGS(off) Gate-Source Cutoff Voltage	-4	-10	-1.5	-4.5		VDS = 15 V, ID = 3 nA	
5	ID(off) Drain Cutoff Current		1		1	nA	VDS = 5 V, VGS = -10 V	150°C
6			1		1	μA		
7	VDS(on) Drain-Source ON Voltage		25		70	mV	VGS = 0, ID = 10 mA	150°C
8	IDSS Saturation Drain Current (Note 2)	500		200		mA	VDS = 10 V, VGS = 0	
9	rDS(on) Static Drain-Source ON Resistance	1.0	2.5	2	7	Ω	VGS = 0 V, ID = 10 mA	150°C
10	rdS(on) Drain-Source ON Resistance	1.0	2.5	2	7	Ω	VGS = 0, ID = 0	
11	CSGO Source-Gate OFF Capacitance		30		30	pF	VSG = 15 V, ID = 0	f = 1 MHz
12	CDGO Drain-Gate OFF Capacitance		30		30	pF	VDG = 15 V, IS = 0	
13	CSG+CDG Source Gate Plus Drain Gate On Capacitance		160		160	pF	VDS = 0, VGS = 0	f = 1 MHz
14	td Turn-ON Delay Time		15		15	ns	VDD = 1.5 V, ID(on) = 30 mA, VGS(on) = 0, VGS(off) = -12 V (U290) - 7 V (U291)	
15	tr Rise Time		20		20	ns		f = 1 MHz
16	tOFF * Turn-OFF Time		15		15	ns		
17	tf Fall Time		20		20	ns		f = 1 MHz

NOTES:

1. Derate linearly at the rate of 2.3 mW/°C.
2. Pulse test required pulswidth 300 μs, duty cycle ≤ 3%.



Performance Curves PS

See Page 4-61

U300 U301



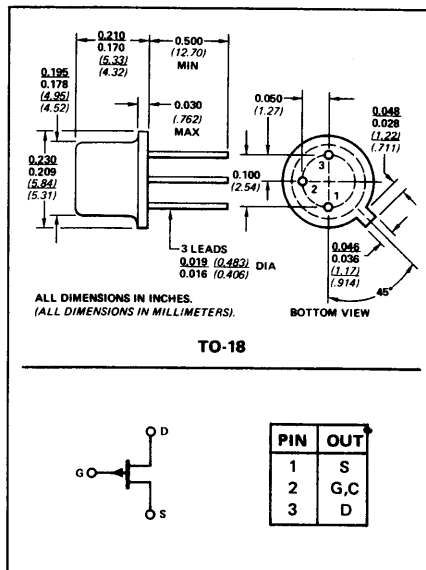
P-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

FOR INDUSTRIAL AND CONSUMER AMPLIFIER APPLICATIONS

- High g_{fs} , 12,000 μmhos typical at $V_{GS} = 0$
- $I_{D(off)}$ < 100 pA
- Low Noise, 40 nV/ $\sqrt{\text{Hz}}$ at 1 kHz

*ABSOLUTE MAXIMUM RATINGS (25°C)

Reverse Gate-Drain or Gate-Source Voltage (Note 1)	40 V
Gate Current	50 mA
Total Device Dissipation, Free-Air (Derate 2.4 mW/°C)	300 mW
Storage Temperature Range	-65 to +150°C
Lead Temperature (1/16" from case for 60 seconds)	300°C



*ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)

Characteristic		U300		U301		Unit	Test Conditions	
		Min	Max	Min	Max			
1	I_{GSS} Gate Reverse Current		100		100	pA	$V_{GS} = 20 \text{ V}, V_{DS} = 0$	
2	$I_{D(off)}$ Drain Cutoff Current		-100		-100		$V_{DS} = -15 \text{ V}, V_{GS} = 12 \text{ V}$	
3	BV_{GSS} Gate-Source Breakdown Voltage	40		40			$I_G = 1.0 \mu\text{A}, V_{DS} = 0$	
4	$V_{GS(off)}$ Gate-Source Cutoff Voltage	5.0	10.0	2.5	6.0	V	$V_{DS} = -15 \text{ V}, I_D = -1 \text{ nA}$	
5	I_{DSS} Saturation Drain Current	-30	-90	-15	-60		$V_{DS} = -15 \text{ V}, V_{GS} = 0$	
6	$r_{DS(on)}$ Static Drain-Source ON Resistance		60		100		$V_{GS} = 0, I_D = -1 \text{ mA}$	
7	g_{fs} Common-Source Forward Transconductance	8000	12,000			μmho	$I_D = -15 \text{ mA}$	
8				7000	11,000		$I_D = -7 \text{ mA}$	
9							$f = 1 \text{ kHz}$	
10	C_{iss} Common-Source Input Capacitance		20		20	pF	$V_{DS} = -15 \text{ V}$	
11	C_{rss} Common-Source Reverse Transfer Capacitance		5.5		5.5		$I_D = -15 \text{ mA}$	
12							$I_D = -7 \text{ mA}$	
13	$\bar{e}_n$ Short-Circuit Equivalent Input Spot Noise Voltage		40			$\frac{\text{nV}}{\sqrt{\text{Hz}}}$	$I_D = -15 \text{ mA}$	
14					40		$I_D = -7 \text{ mA}$	
							$f = 1 \text{ kHz}$	

NOTES:

1. Due to symmetrical geometry these units may be operated with source and drain leads interchanged.
2. Pulse test duration = 2 ms.

PS

Performance Curves PS

See Page 4-61

P-CHANNEL SILICON JUNCTION FIELD-EFFECT TRANSISTORS

FOR ANALOG SWITCHES, COMMUTATORS
AND CHOPPERS

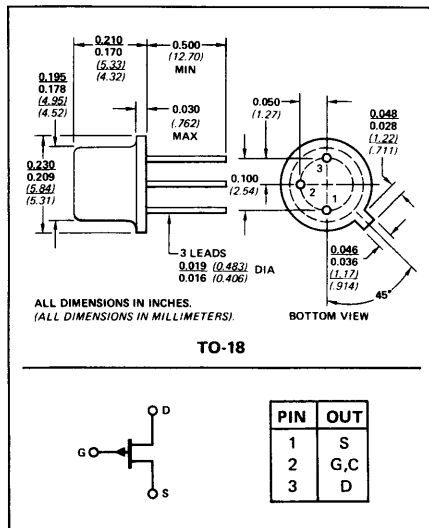
- Replacement for 2N5114, 2N5115, and 2N5116 in applications where switching times are not critical
- $r_{DS(on)} < 85$ ohms on U304
- $I_{D(off)} < 500$ pA

ABSOLUTE MAXIMUM RATINGS (25°C)

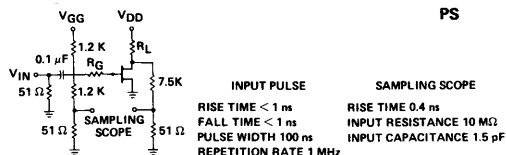
Reverse Gate-Drain or Gate-Source Voltage 30 V
 Gate Current 50 mA
 Total Device Dissipation, Free-Air
 (Derate 2.8 mW/°C) 350 mW
 Storage Temperature Range -65 to +150°C
 Lead Temperature
 (1/16" from case for 60 seconds) 300°C

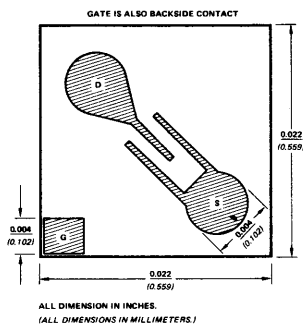
ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)

Characteristic			U304		U305		U306		Unit	Test Conditions				
			Min	Max	Min	Max	Min	Max						
1	S T A T I C	IGSS	Gate Reverse Current		500		500		500	pA	VGS = 20 V, VDS = 0	150°C		
2					1.0		1.0		1.0	μA				
3		BVGSS	Gate-Source Breakdown Voltage	30		30		30		V	IG = 1 μA, VDS = 0			
4		VGS(off)	Gate-Source Cutoff Voltage	5	10	3	6	1	4		VDS = -15 V, ID = -1 μA			
5		VDS(on)	Drain-Source ON Voltage		-1.3		-0.8		-0.6		VGS = 0 ID = -15 mA = U304 - 7 mA = U305 - 3 mA = U306			
6		IDSS	Saturation Drain Current	-30	-90	-15	-60	-5	-25		mA	VDS = -15 V, VGS = 0		
7		D Y N	ID(off)	Drain Cutoff Current		-500		-500		-500	pA	VDS = -15 V, VGS = 12 V = U304 7 V = U305 5 V = U306	150°C	
8						-1.0		-1.0		-1.0	μA			
9			rDS(on)	Static Drain-Source ON Resistance		85		110		175	Ω	VGS = 0, ID = -1 mA		
10	rds(on)		Drain-Source ON Resistance		85		110		175	Ω	VGS = 0, ID = 0			
11	D Y N	Ciss	Common-Source Input Capacitance		27		27		27	pF	VDS = -15 V, VGS = 0			
12		Crss	Common-Source Reverse Transfer Capacitance		7		7		7		VDS = 0, VGS = 12 V = U304 7 V = U305 5 V = U306			
13	S W I T C H	td	Turn-ON Delay Time		20		25		25	ns		U304	U305	U306
14		tr	Rise Time		15		25		35		VDD	-10 V	-6 V	-6 V
15		t _{off}	Turn-OFF Delay Time		10		15		20		VGG	20 V	12 V	8 V
16		tf	Fall Time		25		40		60		RL	430 Ω	910 Ω	2 kΩ
											RG	100 Ω	220 Ω	390 Ω
									ID(on)	-15 mA	-7 mA	-3 mA		



*Due to symmetrical geometry these units may be operated with source and drain leads interchanged.





N-CHANNEL DEPLETION MODE SILICON JUNCTION FIELD-EFFECT TRANSISTOR

APPLICATIONS

- Low Power General Purpose Amplifiers where a Combination of Low Gate Leakage and Noise Voltage are Required

PRINCIPAL DEVICES

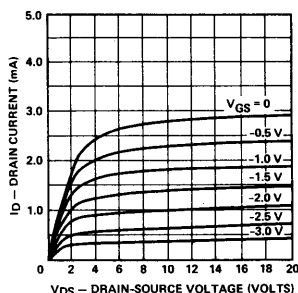
2N3066-71 2N3089-89A
2N3365-67 2N3452-57
2N5647-49

PACKAGE TYPES

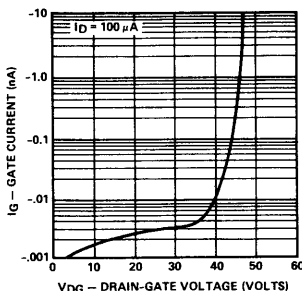
TO-18 TO-72

PERFORMANCE CURVES (25°C unless otherwise noted)

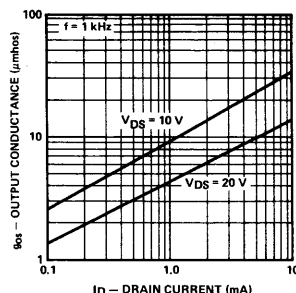
Output Characteristic



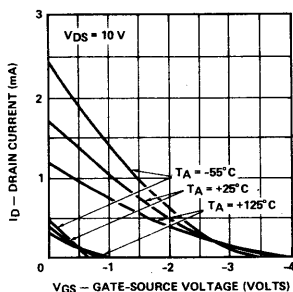
Gate Operating Current vs Drain-Gate Voltage



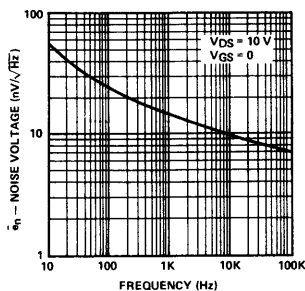
Common-Source Output Conductance vs Drain Current



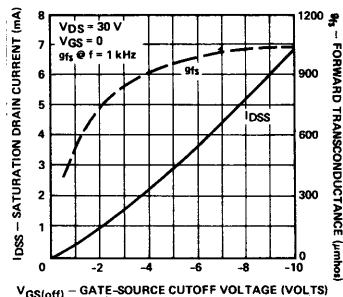
Transfer Characteristics



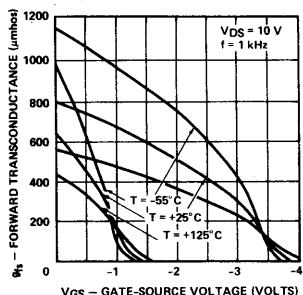
Equivalent Input Noise Voltage vs Frequency



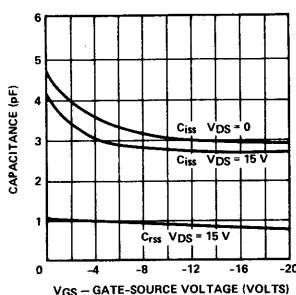
Drain Current & Transconductance vs Gate-Source Cutoff Voltage



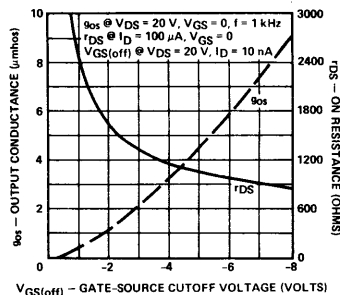
Transconductance Characteristics

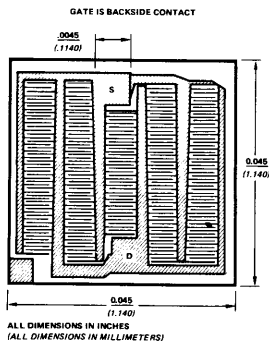


Common-Source Capacitance vs Gate-Source Voltage



ON Resistance & Output Conductance vs Gate-Source Cutoff Voltage





N-CHANNEL DEPLETION MODE JUNCTION FIELD-EFFECT TRANSISTOR

APPLICATIONS

- Ultra Low ON Resistance Switches
- High Gain Audio or Power Amplifiers

PRINCIPAL DEVICES

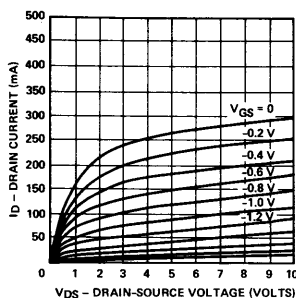
U290-91, E105-07

PACKAGE TYPES

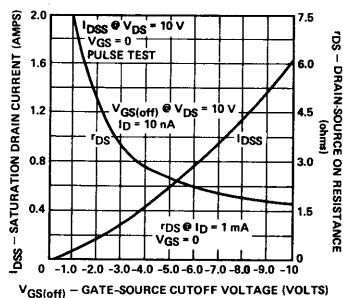
TO-39, TO-52, TO-106

PERFORMANCE CURVES (25°C unless otherwise noted)

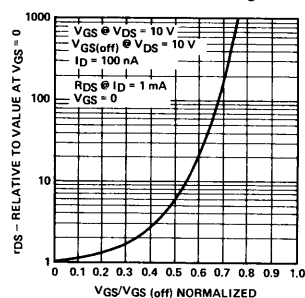
Output Characteristic



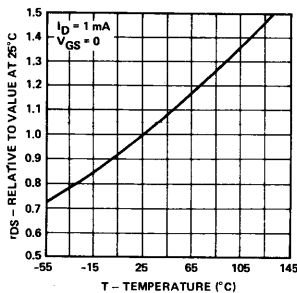
Saturation Drain Current and
Drain-Source 'ON' Resistance vs
Gate-Source Cutoff Voltage



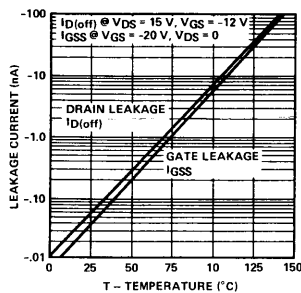
Drain-Source 'ON' Resistance vs
Gate-Source Voltage



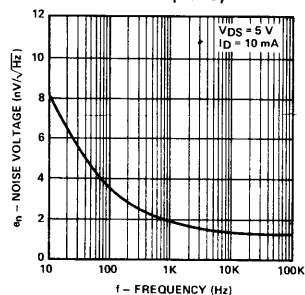
Drain-Source 'ON' Resistance vs
Ambient Temperature



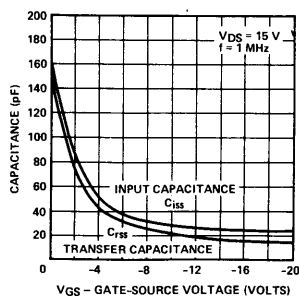
Leakage Currents vs
Ambient Temperature

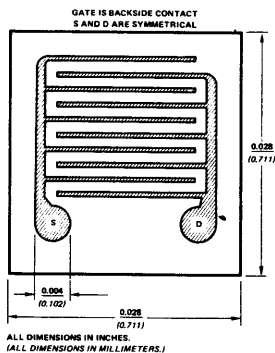


Equivalent Input Noise Voltage vs
Frequency



Common-Source Capacitance
vs Gate-Source Voltage





P-CHANNEL DEPLETION MODE SILICON JUNCTION FIELD-EFFECT TRANSISTOR

APPLICATIONS

- High g_{fs} and Low Noise (10 to 40 nV at 1 kHz) Suitable for General Purpose Amplifiers
- High g_{fs} , Low ON Resistance and Capacitance and Low Switching Aperture Times Allows Operation in Analog Switching Applications

PRINCIPAL DEVICES

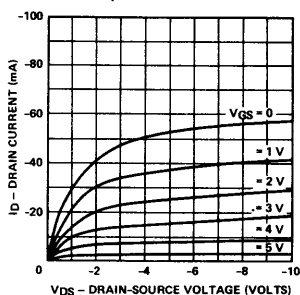
2N5114-16, U300-01, U304-06,
E174-6, E270-1

PACKAGE TYPES:

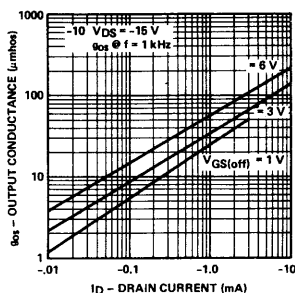
TO-18, TO106

PERFORMANCE CURVES (25°C unless otherwise noted)

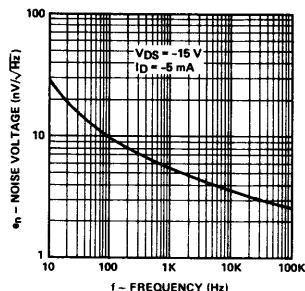
Output Characteristic



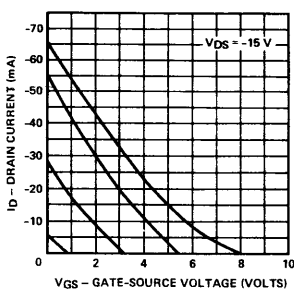
Common-Source Output Conductance
vs Drain Current



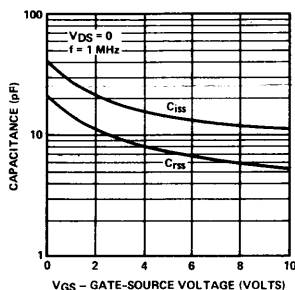
Equivalent Input Noise Voltage
vs Frequency



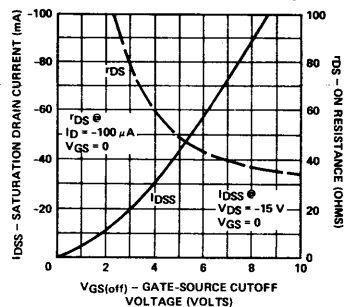
Transfer Characteristics



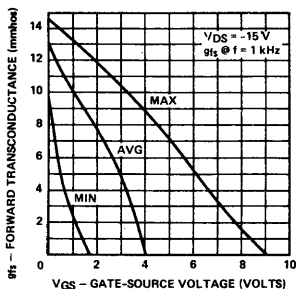
Common-Source Capacitance
vs Gate-Source Voltage



Saturation Drain Current and
Drain-Source ON Resistance
vs. Gate-Source Cutoff Voltage



Transconductance
Characteristics



Gate Operating Current
vs Drain-Gate Voltage

